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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, I ² C, IrDA, LINbus, MMC/SD, QSPI, SAI, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, PWM, WDT
Number of I/O	83
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	160K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 16x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l451vet6

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Table 6. STM32L451xx peripherals interconnect matrix (continued)

Interconnect source	Interconnect destination	Interconnect action	Run	Sleep	Low-power run	Low-power sleep	Stop 0 / Stop 1	Stop 2
GPIO	TIMx	External trigger	Y	Y	Y	Y	-	-
	LPTIMERx	External trigger	Y	Y	Y	Y	Y	Y ⁽¹⁾
	ADCx DAC1 DFSDM1	Conversion external trigger	Y	Y	Y	Y	-	-

1. LPTIM1 only.

3.14 Interrupts and events

3.14.1 Nested vectored interrupt controller (NVIC)

The devices embed a nested vectored interrupt controller able to manage 16 priority levels, and handle up to 67 maskable interrupt channels plus the 16 interrupt lines of the Cortex[®]-M4.

The NVIC benefits are the following:

- Closely coupled NVIC gives low latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Allows early processing of interrupts
- Processing of late arriving higher priority interrupts
- Support for tail chaining
- Processor state automatically saved on interrupt entry, and restored on interrupt exit, with no instruction overhead

The NVIC hardware block provides flexible interrupt management features with minimal interrupt latency.

3.14.2 Extended interrupt/event controller (EXTI)

The extended interrupt/event controller consists of 37 edge detector lines used to generate interrupt/event requests and wake-up the system from Stop mode. Each external line can be independently configured to select the trigger event (rising edge, falling edge, both) and can be masked independently. A pending register maintains the status of the interrupt requests. The internal lines are connected to peripherals with wakeup from Stop mode capability. The EXTI can detect an external line with a pulse width shorter than the internal clock period. Up to 83 GPIOs can be connected to the 16 external interrupt lines.

without having any impact on the timing of “injected” conversions

- “injected” conversions for precise timing and with high conversion priority

Table 10. DFSDM1 implementation

DFSDM features	DFSDM1
Number of channels	8
Number of filters	4
Input from internal ADC	-
Supported trigger sources	10
Pulses skipper	-
ID registers support	-

3.22 Random number generator (RNG)

All devices embed an RNG that delivers 32-bit random numbers generated by an integrated analog circuit.

3.23 Timers and watchdogs

The STM32L451xx includes one advanced control timers, up to five general-purpose timers, two basic timers, two low-power timers, two watchdog timers and a SysTick timer. The table below compares the features of the advanced control, general purpose and basic timers.

Table 11. Timer feature comparison

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
Advanced control	TIM1	16-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	3
General-purpose	TIM2	32-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	No
General-purpose	TIM3	16-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	No
General-purpose	TIM15	16-bit	Up	Any integer between 1 and 65536	Yes	2	1
General-purpose	TIM16	16-bit	Up	Any integer between 1 and 65536	Yes	1	1
Basic	TIM6	16-bit	Up	Any integer between 1 and 65536	Yes	0	No

Table 14. SAI implementation

SAI features	Support ⁽¹⁾
I2S, LSB or MSB-justified, PCM/DSP, TDM, AC'97	X
Mute mode	X
Stereo/Mono audio frame capability.	X
16 slots	X
Data size configurable: 8-, 10-, 16-, 20-, 24-, 32-bit	X
FIFO Size	X (8 Word)
SPDIF	X

1. X: supported

3.30 Controller area network (CAN)

The CAN is compliant with specifications 2.0A and B (active) with a bit rate up to 1 Mbit/s. It can receive and transmit standard frames with 11-bit identifiers as well as extended frames with 29-bit identifiers. It has three transmit mailboxes, two receive FIFOs with 3 stages and 14 scalable filter banks.

The CAN peripheral supports:

- Supports CAN protocol version 2.0 A, B Active
- Bit rates up to 1 Mbit/s
- Transmission
 - Three transmit mailboxes
 - Configurable transmit priority
- Reception
 - Two receive FIFOs with three stages
 - 14 Scalable filter banks
 - Identifier list feature
 - Configurable FIFO overrun
- Time-triggered communication option
 - Disable automatic retransmission mode
 - 16-bit free running timer
 - Time Stamp sent in last two data bytes
- Management
 - Maskable interrupts
 - Software-efficient mailbox mapping at a unique address space

3.31 Secure digital input/output and MultiMediaCards Interface (SDMMC)

The card host interface (SDMMC) provides an interface between the APB peripheral bus and MultiMediaCards (MMCs), SD memory cards and SDIO cards.

Table 17. Alternate function AF0 to AF7⁽¹⁾ (continued)

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7
		SYS_AF	TIM1/TIM2 LPTIM1	I2C4/TIM1/ TIM2/TIM3	I2C4/USART2/ CAN1/TIM1	I2C1/I2C2/ I2C3/I2C4	SPI1/SPI2/I2C4	SPI3/DFSDM/ COMP1	USART1/ USART2/ USART3
Port D	PD0	-	-	-	-	-	SPI2_NSS	-	-
	PD1	-	-	-	-	-	SPI2_SCK	-	-
	PD2	TRACED2	-	TIM3_ETR	-	-	-	-	USART3_RTS_ DE
	PD3	-	-	-	-	-	SPI2_MISO	DFSDM1_ DATIN0	USART2_CTS
	PD4	-	-	-	-	-	SPI2_MOSI	DFSDM1_ CKIN0	USART2_RTS_ DE
	PD5	-	-	-	-	-	-	-	USART2_TX
	PD6	-	-	-	-	-	-	DFSDM1_ DATIN1	USART2_RX
	PD7	-	-	-	-	-	-	DFSDM1_ CKIN1	USART2_CK
	PD8	-	-	-	-	-	-	-	USART3_TX
	PD9	-	-	-	-	-	-	-	USART3_RX
	PD10	-	-	-	-	-	-	-	USART3_CK
	PD11	-	-	-	-	I2C4_SMBA	-	-	USART3_CTS
	PD12	-	-	-	-	I2C4_SCL	-	-	USART3_RTS_ DE
	PD13	-	-	-	-	I2C4_SDA	-	-	-
	PD14	-	-	-	-	-	-	-	-
	PD15	-	-	-	-	-	-	-	-

Table 19. STM32L451xx memory map and peripheral register boundary addresses⁽¹⁾

Bus	Boundary address	Size(bytes)	Peripheral
AHB2	0x5006 0800 - 0x5006 0BFF	1 KB	RNG
	0x5004 0400 - 0x5006 07FF	158 KB	Reserved
	0x5004 0000 - 0x5004 03FF	1 KB	ADC
	0x5000 0000 - 0x5003 FFFF	16 KB	Reserved
	0x4800 2000 - 0x4FFF FFFF	~127 MB	Reserved
	0x4800 1C00 - 0x4800 1FFF	1 KB	GPIOH
	0x4800 1400 - 0x4800 1BFF	2 KB	Reserved
	0x4800 1000 - 0x4800 13FF	1 KB	GPIOE
	0x4800 0C00 - 0x4800 0FFF	1 KB	GPIOD
	0x4800 0800 - 0x4800 0BFF	1 KB	GPIOC
	0x4800 0400 - 0x4800 07FF	1 KB	GPIOB
	0x4800 0000 - 0x4800 03FF	1 KB	GPIOA
-	0x4002 4400 - 0x47FF FFFF	~127 MB	Reserved
AHB1	0x4002 4000 - 0x4002 43FF	1 KB	TSC
	0x4002 3400 - 0x4002 3FFF	1 KB	Reserved
	0x4002 3000 - 0x4002 33FF	1 KB	CRC
	0x4002 2400 - 0x4002 2FFF	3 KB	Reserved
	0x4002 2000 - 0x4002 23FF	1 KB	FLASH registers
	0x4002 1400 - 0x4002 1FFF	3 KB	Reserved
	0x4002 1000 - 0x4002 13FF	1 KB	RCC
	0x4002 0800 - 0x4002 0FFF	2 KB	Reserved
	0x4002 0400 - 0x4002 07FF	1 KB	DMA2
	0x4002 0000 - 0x4002 03FF	1 KB	DMA1
	0x4001 6400 - 0x4001 FFFF	39 KB	Reserved
APB2	0x4001 6000 - 0x4000 63FF	1 KB	DFSDM
	0x4001 5800 - 0x4001 5FFF	2 KB	Reserved
	0x4001 5400 - 0x4000 57FF	1 KB	SAI1
	0x4001 4800 - 0x4000 53FF	3 KB	Reserved
	0x4001 4400 - 0x4001 47FF	1 KB	TIM16
	0x4001 4000 - 0x4001 43FF	1 KB	TIM15
	0x4001 3C00 - 0x4001 3FFF	1 KB	Reserved
	0x4001 3800 - 0x4001 3BFF	1 KB	USART1
	0x4001 3400 - 0x4001 37FF	1 KB	Reserved
	0x4001 3000 - 0x4001 33FF	1 KB	SPI1



**Table 27. Current consumption in Run and Low-power run modes, code with data processing
running from Flash, ART enable (Cache ON Prefetch OFF)**

Symbol	Parameter	Conditions			TYP					MAX ⁽¹⁾					Unit
		-	Voltage scaling	f _{HCLK}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD_ALL} (Run)	Supply current in Run mode	f _{HCLK} = f _{HSE} up to 48MHz included, bypass mode PLL ON above 48 MHz all peripherals disable	Range 2	26 MHz	2.35	2.40	2.50	2.65	3.00	2.65	2.75	2.90	3.20	3.75	mA
				16 MHz	1.50	1.55	1.65	1.80	2.15	1.70	1.75	1.95	2.20	2.80	
				8 MHz	0.815	0.845	0.940	1.10	1.45	0.95	1.00	1.15	1.45	2.00	
				4 MHz	0.465	0.495	0.595	0.760	1.10	0.55	0.60	0.75	1.05	1.60	
				2 MHz	0.295	0.320	0.420	0.580	0.910	0.35	0.40	0.55	0.85	1.40	
				1 MHz	0.205	0.235	0.330	0.495	0.825	0.25	0.30	0.45	0.75	1.30	
				100 kHz	0.130	0.155	0.250	0.415	0.745	0.15	0.25	0.40	0.65	1.25	
			Range 1	80 MHz	8.45	8.50	8.65	8.90	9.25	9.45	9.50	9.75	10.10	10.75	
				72 MHz	7.65	7.70	7.85	8.05	8.45	8.50	8.60	8.80	9.15	9.85	
				64 MHz	6.80	6.85	7.00	7.20	7.60	7.60	7.70	7.90	8.25	8.90	
				48 MHz	5.10	5.15	5.25	5.45	5.85	5.70	5.80	6.00	6.35	7.00	
				32 MHz	3.45	3.50	3.60	3.80	4.20	3.85	3.95	4.15	4.50	5.15	
				24 MHz	2.60	2.65	2.80	2.95	3.35	2.95	3.05	3.20	3.55	4.20	
				16 MHz	1.80	1.85	1.95	2.15	2.50	2.00	2.10	2.30	2.60	3.25	
I _{DD_ALL} (LPRun)	Supply current in Low-power run mode	f _{HCLK} = f _{MSI} all peripherals disable	2 MHz	225	260	365	550	900	275	335	470	770	1400	μA	
			1 MHz	130	160	270	450	800	170	225	375	670	1300		
			400 kHz	73.0	99.5	205	385	735	105	165	325	600	1250		
			100 kHz	38.0	71.0	175	355	705	70	140	315	565	1200		

1. Guaranteed by characterization results, unless otherwise specified.

Table 28. Current consumption in Run and Low-power run modes, code with data processing running from Flash, ART disable

Symbol	Parameter	Conditions			TYP					MAX ⁽¹⁾					Unit
		-	Voltage scaling	f _{HCLK}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD_ALL} (Run)	Supply current in Run mode	f _{HCLK} = f _{HSE} up to 48MHz included, bypass mode PLL ON above 48 MHz all peripherals disable	Range 2	26 MHz	2.75	2.80	2.90	3.10	3.40	3.15	3.25	3.40	3.70	4.30	mA
				16 MHz	1.95	2.00	2.10	2.25	2.60	2.25	2.30	2.50	2.75	3.35	
				8 MHz	1.10	1.15	1.25	1.40	1.75	1.25	1.35	1.50	1.75	2.35	
				4 MHz	0.640	0.670	0.765	0.935	1.25	0.75	0.80	0.95	1.25	1.80	
				2 MHz	0.380	0.405	0.505	0.670	1.00	0.45	0.50	0.65	0.95	1.50	
				1 MHz	0.250	0.275	0.375	0.540	0.865	0.30	0.35	0.50	0.80	1.35	
				100 kHz	0.135	0.160	0.255	0.420	0.750	0.15	0.25	0.40	0.65	1.25	
			Range 1	80 MHz	8.85	8.90	9.05	9.30	9.70	10.0	10.5	10.5	11.0	11.5	
				72 MHz	8.00	8.05	8.20	8.40	8.85	9.05	9.15	9.35	9.70	10.5	
				64 MHz	7.90	7.95	8.10	8.35	8.75	8.95	9.10	9.35	9.70	10.5	
				48 MHz	6.60	6.65	6.80	7.05	7.45	7.55	7.65	7.90	8.30	9.00	
				32 MHz	4.75	4.80	4.95	5.15	5.55	5.40	5.50	5.75	6.10	6.80	
				24 MHz	3.60	3.65	3.80	4.00	4.35	4.10	4.20	4.40	4.75	5.40	
				16 MHz	2.60	2.65	2.75	2.95	3.35	3.00	3.05	3.25	3.60	4.25	
I _{DD_ALL} (LPRun)	Supply current in Low-power run	f _{HCLK} = f _{MSI} all peripherals disable	2 MHz	340	360	470	650	1000	400	455	575	880	1550	μA	
			1 MHz	175	215	320	500	855	225	285	420	720	1350		
			400 kHz	89.5	120	225	405	760	130	185	340	620	1250		
			100 kHz	42.5	75.5	180	360	715	75	145	320	575	1200		

1. Guaranteed by characterization results, unless otherwise specified.

Table 33. Current consumption in Sleep and Low-power sleep modes, Flash ON

Symbol	Parameter	Conditions			TYP					MAX ⁽¹⁾					Unit
		-	Voltage scaling	f _{HCLK}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD_ALL} (Sleep)	Supply current in sleep mode,	f _{HCLK} = f _{HSE} up to 48 MHz included, bypass mode pll ON above 48 MHz all peripherals disable	Range 2	26 MHz	0.700	0.730	0.830	1.00	1.35	0.80	0.90	1.05	1.30	1.90	mA
				16 MHz	0.475	0.505	0.605	0.775	1.10	0.55	0.65	0.80	1.05	1.65	
				8 MHz	0.300	0.325	0.425	0.590	0.920	0.35	0.45	0.60	0.85	1.45	
				4 MHz	0.210	0.235	0.335	0.500	0.830	0.25	0.30	0.45	0.75	1.35	
				2 MHz	0.165	0.190	0.290	0.455	0.785	0.20	0.25	0.40	0.70	1.25	
				1 MHz	0.145	0.170	0.265	0.430	0.760	0.15	0.25	0.40	0.65	1.25	
				100 kHz	0.125	0.150	0.245	0.410	0.740	0.15	0.20	0.35	0.65	1.20	
			Range 1	80 MHz	2.30	2.35	2.45	2.65	3.05	2.55	2.65	2.85	3.15	3.80	
				72 MHz	2.10	2.15	2.25	2.45	2.80	2.35	2.40	2.60	2.90	3.55	
				64 MHz	1.90	1.90	2.05	2.25	2.60	2.10	2.20	2.35	2.70	3.35	
				48 MHz	1.40	1.40	1.55	1.75	2.15	1.60	1.65	1.85	2.15	2.80	
				32 MHz	0.970	1.00	1.15	1.30	1.70	1.10	1.20	1.40	1.70	2.35	
				24 MHz	0.765	0.800	0.920	1.10	1.50	0.90	0.95	1.15	1.45	2.10	
				16 MHz	0.555	0.590	0.705	0.895	1.25	0.65	0.75	0.90	1.20	1.85	
I _{DD_ALL} (LPSleep)	Supply current in low-power sleep mode	f _{HCLK} = f _{MSI} all peripherals disable	2 MHz	76.0	110	215	395	745	120	185	355	610	1250	μA	
			1 MHz	54.0	86.5	195	370	725	88.5	160	335	585	1250		
			400 kHz	39.0	70.5	175	355	710	68.5	140	320	570	1200		
			100 kHz	35.5	75.0	195	345	715	66.0	130	305	560	1200		

1. Guaranteed by characterization results, unless otherwise specified.



Table 36. Current consumption in Stop 1 mode

Symbol	Parameter	Conditions		TYP					MAX ⁽¹⁾					Unit
		-	V _{DD}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD_ALL} (Stop 1)	Supply current in Stop 1 mode, RTC disabled	-	1.8 V	9.85	29.0	100	225	430	17.0	49.5	185	395	850	μA
			2.4 V	9.85	29.5	100	225	435	17.0	49.5	185	395	850	
			3 V	9.90	29.5	100	225	435	17.5	50.0	185	400	850	
			3.6 V	10.0	28.0	105	230	410	17.5	50.5	190	405	860	
I _{DD_ALL} (Stop 1 with RTC)	Supply current in stop 1 mode, RTC enabled	RTC clocked by LSI	1.8 V	10.5	29.5	100	225	430	17.0	50.0	185	395	840	μA
			2.4 V	10.5	29.5	100	225	435	17.0	50.5	185	395	845	
			3 V	10.5	30.0	105	225	435	17.5	50.5	185	400	855	
			3.6 V	10.5	30.0	105	230	440	17.5	51.5	190	405	860	
		RTC clocked by LSE bypassed, at 32768 Hz	1.8 V	10.0	29.5	100	225	435	-	-	-	-	-	
			2.4 V	10.0	29.5	100	225	435	-	-	-	-	-	
			3 V	10.5	30.0	105	225	440	-	-	-	-	-	
			3.6 V	11.0	30.5	105	230	440	-	-	-	-	-	
		RTC clocked by LSE quartz ⁽²⁾ in low drive mode	1.8 V	10.0	29.0	99.5	220	435	-	-	-	-	-	
			2.4 V	10.0	29.0	99.5	220	435	-	-	-	-	-	
			3 V	10.0	29.0	100	220	440	-	-	-	-	-	
			3.6 V	10.5	29.5	100	225	440	-	-	-	-	-	
I _{DD_ALL} (wakeup from Stop1)	Supply current during wakeup from Stop 1	Wakeup clock MSI = 48 MHz, voltage Range 1. See ⁽³⁾ .	3 V	1.15	-	-	-	-	-	-	-	-	-	mA
		Wakeup clock MSI = 4 MHz, voltage Range 2. See ⁽³⁾ .	3 V	1.20	-	-	-	-	-	-	-	-	-	
		Wakeup clock HSI16 = 16 MHz, voltage Range 1. See ⁽³⁾ .	3 V	1.20	-	-	-	-	-	-	-	-	-	

1. Guaranteed based on test during characterization, unless otherwise specified.

2. Based on characterization done with a 32.768 kHz crystal (MC306-G-06Q-32.768, manufacturer JFVNY) with two 6.8 pF loading capacitors.

3. Wakeup with code execution from Flash. Average value given for a typical wakeup time as specified in [Table 42: Low-power mode wakeup timings](#).

Table 42. Low-power mode wakeup timings⁽¹⁾ (continued)

Symbol	Parameter	Conditions		Typ	Max	Unit
$t_{WUSTOP0}$	Wake up time from Stop 0 mode to Run mode in Flash	Range 1	Wakeup clock MSI = 48 MHz	3.34	4.3	μs
			Wakeup clock HSI16 = 16 MHz	3.7	6.5	
		Range 2	Wakeup clock MSI = 24 MHz	3.8	7.1	
			Wakeup clock HSI16 = 16 MHz	3.7	6.5	
			Wakeup clock MSI = 4 MHz	9.3	7.1	
	Wake up time from Stop 0 mode to Run mode in SRAM1	Range 1	Wakeup clock MSI = 48 MHz	1.85	2.7	
			Wakeup clock HSI16 = 16 MHz	2.68	3	
		Range 2	Wakeup clock MSI = 24 MHz	2.47	3.4	
			Wakeup clock HSI16 = 16 MHz	2.68	3	
			Wakeup clock MSI = 4 MHz	9.67	12.5	
$t_{WUSTOP1}$	Wake up time from Stop 1 mode to Run in Flash	Range 1	Wakeup clock MSI = 48 MHz	6.75	7.6	μs
			Wakeup clock HSI16 = 16 MHz	7.14	8	
		Range 2	Wakeup clock MSI = 24 MHz	7	7.82	
			Wakeup clock HSI16 = 16 MHz	7.14	7.9	
	Wake up time from Stop 1 mode to Run mode in SRAM1	Range 1	Wakeup clock MSI = 48 MHz	5.21	5.9	
			Wakeup clock HSI16 = 16 MHz	6.23	6.9	
		Range 2	Wakeup clock MSI = 24 MHz	5.73	6.4	
			Wakeup clock HSI16 = 16 MHz	6.23	6.9	
			Wakeup clock MSI = 4 MHz	10.9	12.3	
	Wake up time from Stop 1 mode to Low-power run mode in Flash	Regulator in low-power mode (LPR=1 in PWR_CR1)	Wakeup clock MSI = 2 MHz	16.05	19.2	
	Wake up time from Stop 1 mode to Low-power run mode in SRAM1			17.06	20.3	

Table 42. Low-power mode wakeup timings⁽¹⁾ (continued)

Symbol	Parameter	Conditions		Typ	Max	Unit
$t_{WUSTOP2}$	Wake up time from Stop 2 mode to Run mode in Flash	Range 1	Wakeup clock MSI = 48 MHz	7.93	9.1	μs
			Wakeup clock HSI16 = 16 MHz	7.32	8.5	
		Range 2	Wakeup clock MSI = 24 MHz	8.25	9.4	
			Wakeup clock HSI16 = 16 MHz	7.32	8.4	
			Wakeup clock MSI = 4 MHz	11.43	13.3	
	Wake up time from Stop 2 mode to Run mode in SRAM1	Range 1	Wakeup clock MSI = 48 MHz	5.23	6	
			Wakeup clock HSI16 = 16 MHz	6.33	7.1	
		Range 2	Wakeup clock MSI = 24 MHz	5.78	6.5	
			Wakeup clock HSI16 = 16 MHz	6.33	7.1	
			Wakeup clock MSI = 4 MHz	11.37	12.9	
t_{WUSTBY}	Wakeup time from Standby mode to Run mode	Range 1	Wakeup clock MSI = 8 MHz	16.13	18.2	μs
			Wakeup clock MSI = 4 MHz	24.06	26.6	
t_{WUSTBY} SRAM2	Wakeup time from Standby with SRAM2 to Run mode	Range 1	Wakeup clock MSI = 8 MHz	16.09	18.2	μs
			Wakeup clock MSI = 4 MHz	24	26.6	
t_{WUSHDN}	Wakeup time from Shutdown mode to Run mode	Range 1	Wakeup clock MSI = 4 MHz	255.38	316.41	μs

1. Guaranteed by characterization results.

Table 43. Regulator modes transition times⁽¹⁾

Symbol	Parameter	Conditions	Typ	Max	Unit
$t_{WULPRUN}$	Wakeup time from Low-power run mode to Run mode ⁽²⁾	Code run with MSI 2 MHz	5	7	μs
t_{VOST}	Regulator transition time from Range 2 to Range 1 or Range 1 to Range 2 ⁽³⁾	Code run with MSI 24 MHz	20	40	

1. Guaranteed by characterization results.

2. Time until REGLPF flag is cleared in PWR_SR2.

3. Time until VOSF flag is cleared in PWR_SR2.

Table 44. Wakeup time using USART/LPUART⁽¹⁾

Symbol	Parameter	Conditions	Typ	Max	Unit
$t_{WUUSART}$ $t_{WULPUART}$	Wakeup time needed to calculate the maximum USART/LPUART baudrate allowing to wakeup up from stop mode when USART/LPUART clock source is HSI16	Stop 0 mode	-	1.7	μs
		Stop 1 mode and Stop 2 mode	-	8.5	

1. Guaranteed by design.

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the NRST pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

Electromagnetic Interference (EMI)

The electromagnetic field emitted by the device are monitored while a simple application is executed (toggling 2 LEDs through the I/O ports). This emission test is compliant with IEC 61967-2 standard which specifies the test board and the pin loading.

Table 57. EMI characteristics

Symbol	Parameter	Conditions	Monitored frequency band	Max vs. [f _{HSE} /f _{HCLK}]	Unit
				8 MHz/ 80 MHz	
S _{EMI}	Peak level	V _{DD} = 3.6 V, T _A = 25 °C, LQFP100 package compliant with IEC 61967-2	0.1 MHz to 30 MHz	-8	dBμV
			30 MHz to 130 MHz	2	
			130 MHz to 1 GHz	5	
			1 GHz to 2 GHz	8	
			EMI Level	2.5	-

6.3.12 Electrical sensitivity characteristics

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts × (n+1) supply pins). This test conforms to the ANSI/JEDEC standard.

Table 58. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Class	Maximum value ⁽¹⁾	Unit
V _{ESD(HBM)}	Electrostatic discharge voltage (human body model)	T _A = +25 °C, conforming to ANSI/ESDA/JEDEC JS-001	2	2000	V
V _{ESD(CDM)}	Electrostatic discharge voltage (charge device model)	T _A = +25 °C, conforming to ANSI/ESD STM5.3.1	C3	250	

1. Guaranteed by characterization results.

6.3.14 I/O port characteristics

General input/output characteristics

Unless otherwise specified, the parameters given in [Table 61](#) are derived from tests performed under the conditions summarized in [Table 23: General operating conditions](#). All I/Os are designed as CMOS- and TTL-compliant.

Table 61. I/O static characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL}^{(1)}$	I/O input low level voltage	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	-	-	$0.3 \times V_{DDIOx}^{(2)}$	V
	I/O input low level voltage	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	-	-	$0.39 \times V_{DDIOx} - 0.06^{(3)}$	
	I/O input low level voltage	$1.08\text{ V} < V_{DDIOx} < 1.62\text{ V}$	-	-	$0.43 \times V_{DDIOx} - 0.1^{(3)}$	
$V_{IH}^{(1)}$	I/O input high level voltage	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	$0.7 \times V_{DDIOx}^{(2)}$	-	-	V
	I/O input high level voltage	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	$0.49 \times V_{DDIOx} + 0.26^{(3)}$	-	-	
	I/O input high level voltage	$1.08\text{ V} < V_{DDIOx} < 1.62\text{ V}$	$0.61 \times V_{DDIOx} + 0.05^{(3)}$	-	-	
$V_{hys}^{(3)}$	TT_xx, FT_xxx and NRST I/O input hysteresis	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	-	200	-	mV
I_{lkg}	FT_xx input leakage current ⁽³⁾⁽⁴⁾	$V_{IN} \leq \text{Max}(V_{DDXXX})^{(5)(6)}$	-	-	± 100	nA
		$\text{Max}(V_{DDXXX}) \leq V_{IN} \leq \text{Max}(V_{DDXXX}) + 1\text{ V}^{(5)(6)}$	-	-	$650^{(3)(7)}$	
		$\text{Max}(V_{DDXXX}) + 1\text{ V} < V_{IN} \leq 5.5\text{ V}^{(3)(6)}$	-	-	$200^{(7)}$	
	PA11, PA12, and PC3 I/O	$V_{IN} \leq \text{Max}(V_{DDXXX})^{(5)(6)}$	-	-	± 150	
		$\text{Max}(V_{DDXXX}) \leq V_{IN} \leq \text{Max}(V_{DDXXX}) + 1\text{ V}^{(5)(6)}$	-	-	$2500^{(3)}$	
		$\text{Max}(V_{DDXXX}) + 1\text{ V} < V_{IN} \leq 5.5\text{ V}^{(5)(6)}$	-	-	250	
	TT_xx input leakage current	$V_{IN} \leq \text{Max}(V_{DDXXX})^{(7)}$	-	-	± 150	
		$\text{Max}(V_{DDXXX}) \leq V_{IN} < 3.6\text{ V}^{(7)}$	-	-	$2000^{(3)}$	
R_{PU}	Weak pull-up equivalent resistor ⁽⁸⁾	$V_{IN} = V_{SS}$	25	40	55	kΩ
R_{PD}	Weak pull-down equivalent resistor ⁽⁸⁾	$V_{IN} = V_{DDIOx}$	25	40	55	kΩ
C_{IO}	I/O pin capacitance	-	-	5	-	pF

Unless otherwise specified, the parameters given are derived from tests performed under the ambient temperature and supply voltage conditions summarized in [Table 23: General operating conditions](#).

Table 63. I/O AC characteristics⁽¹⁾⁽²⁾

Speed	Symbol	Parameter	Conditions	Min	Max	Unit
00	Fmax	Maximum frequency	C=50 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	5	MHz
			C=50 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	1	
			C=50 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	0.1	
			C=10 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	10	
			C=10 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	1.5	
			C=10 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	0.1	
	Tr/Tf	Output rise and fall time	C=50 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	25	ns
			C=50 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	52	
			C=50 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	140	
			C=10 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	17	
			C=10 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	37	
			C=10 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	110	
01	Fmax	Maximum frequency	C=50 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	25	MHz
			C=50 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	10	
			C=50 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	1	
			C=10 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	50	
			C=10 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	15	
			C=10 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	1	
	Tr/Tf	Output rise and fall time	C=50 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	9	ns
			C=50 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	16	
			C=50 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	40	
			C=10 pF, 2.7 V ≤ V _{DDIOx} ≤ 3.6 V	-	4.5	
			C=10 pF, 1.62 V ≤ V _{DDIOx} ≤ 2.7 V	-	9	
			C=10 pF, 1.08 V ≤ V _{DDIOx} ≤ 1.62 V	-	21	

Table 71. ADC accuracy - limited test conditions 3⁽¹⁾⁽²⁾⁽³⁾

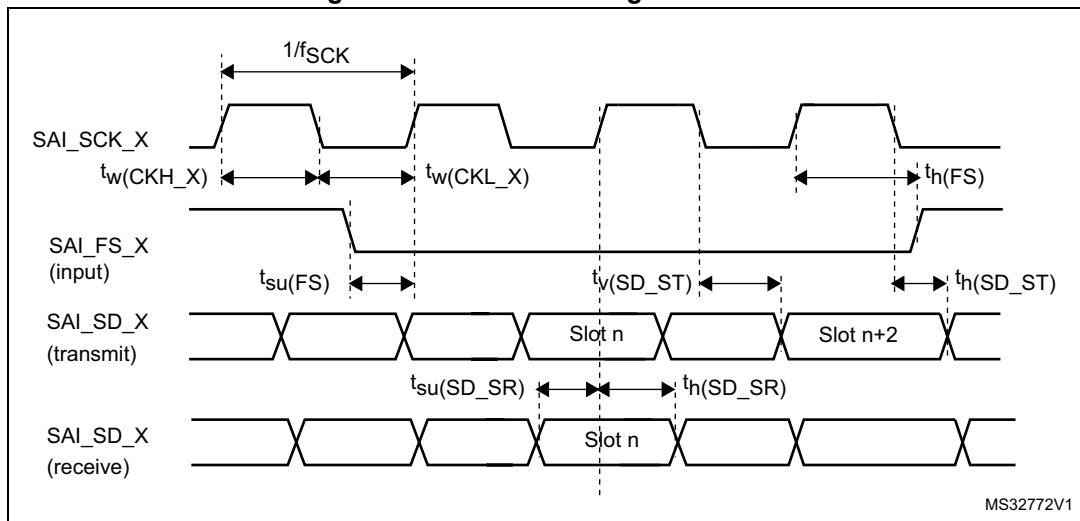
Sym- bol	Parameter	Conditions ⁽⁴⁾		Min	Typ	Max	Unit
ET	Total unadjusted error	Single ended	Fast channel (max speed)	-	5.5	7.5	LSB
			Slow channel (max speed)	-	4.5	6.5	
		Differential	Fast channel (max speed)	-	4.5	7.5	
			Slow channel (max speed)	-	4.5	5.5	
EO	Offset error	Single ended	Fast channel (max speed)	-	2	5	
			Slow channel (max speed)	-	2.5	5	
		Differential	Fast channel (max speed)	-	2	3.5	
			Slow channel (max speed)	-	2.5	3	
EG	Gain error	Single ended	Fast channel (max speed)	-	4.5	7	
			Slow channel (max speed)	-	3.5	6	
		Differential	Fast channel (max speed)	-	3.5	4	
			Slow channel (max speed)	-	3.5	5	
ED	Differential linearity error	Single ended	Fast channel (max speed)	-	1.2	1.5	
			Slow channel (max speed)	-	1.2	1.5	
		Differential	Fast channel (max speed)	-	1	1.2	
			Slow channel (max speed)	-	1	1.2	
EL	Integral linearity error	Single ended	Fast channel (max speed)	-	3	3.5	
			Slow channel (max speed)	-	2.5	3.5	
		Differential	Fast channel (max speed)	-	2	2.5	
			Slow channel (max speed)	-	2	2.5	
ENOB	Effective number of bits	Single ended	Fast channel (max speed)	10	10.4	-	bits
			Slow channel (max speed)	10	10.4	-	
		Differential	Fast channel (max speed)	10.6	10.7	-	
			Slow channel (max speed)	10.6	10.7	-	
SINAD	Signal-to-noise and distortion ratio	Single ended	Fast channel (max speed)	62	64	-	dB
			Slow channel (max speed)	62	64	-	
		Differential	Fast channel (max speed)	65	66	-	
			Slow channel (max speed)	65	66	-	
SNR	Signal-to-noise ratio	Single ended	Fast channel (max speed)	63	65	-	
			Slow channel (max speed)	63	65	-	
		Differential	Fast channel (max speed)	66	67	-	
			Slow channel (max speed)	66	67	-	

6.3.21 Comparator characteristics

Table 76. COMP characteristics⁽¹⁾

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V _{DDA}	Analog supply voltage	-		1.62	-	3.6	V
V _{IN}	Comparator input voltage range	-		0	-	V _{DDA}	
V _{BG} ⁽²⁾	Scaler input voltage	-		V _{REFINT}			
V _{SC}	Scaler offset voltage	-		-	±5	±10	mV
I _{DDA} (SCALER)	Scaler static consumption from V _{DDA}	BRG_EN=0 (bridge disable)		-	200	300	nA
		BRG_EN=1 (bridge enable)		-	0.8	1	µA
t _{START_SCALER}	Scaler startup time	-		-	100	200	µs
t _{START}	Comparator startup time to reach propagation delay specification	High-speed mode	V _{DDA} ≥ 2.7 V	-	-	5	µs
			V _{DDA} < 2.7 V	-	-	7	
		Medium mode	V _{DDA} ≥ 2.7 V	-	-	15	
			V _{DDA} < 2.7 V	-	-	25	
		Ultra-low-power mode		-	-	40	
t _D ⁽³⁾	Propagation delay with 100 mV overdrive	High-speed mode	V _{DDA} ≥ 2.7 V	-	55	80	ns
			V _{DDA} < 2.7 V	-	65	100	
		Medium mode		-	0.55	0.9	µs
		Ultra-low-power mode		-	4	7	
V _{offset}	Comparator offset error	Full common mode range	-	-	±5	±20	mV
V _{hys}	Comparator hysteresis	No hysteresis		-	0	-	mV
		Low hysteresis		-	8	-	
		Medium hysteresis		-	15	-	
		High hysteresis		-	27	-	

Figure 37. SAI slave timing waveforms



SDMMC characteristics

Unless otherwise specified, the parameters given in [Table 89](#) for SDIO are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in [Table 23: General operating conditions](#), with the following configuration:

- Output speed is set to $OSPEEDRy[1:0] = 11$
- Capacitive load $C = 30$ pF
- Measurement points are done at CMOS levels: $0.5 \times V_{DD}$

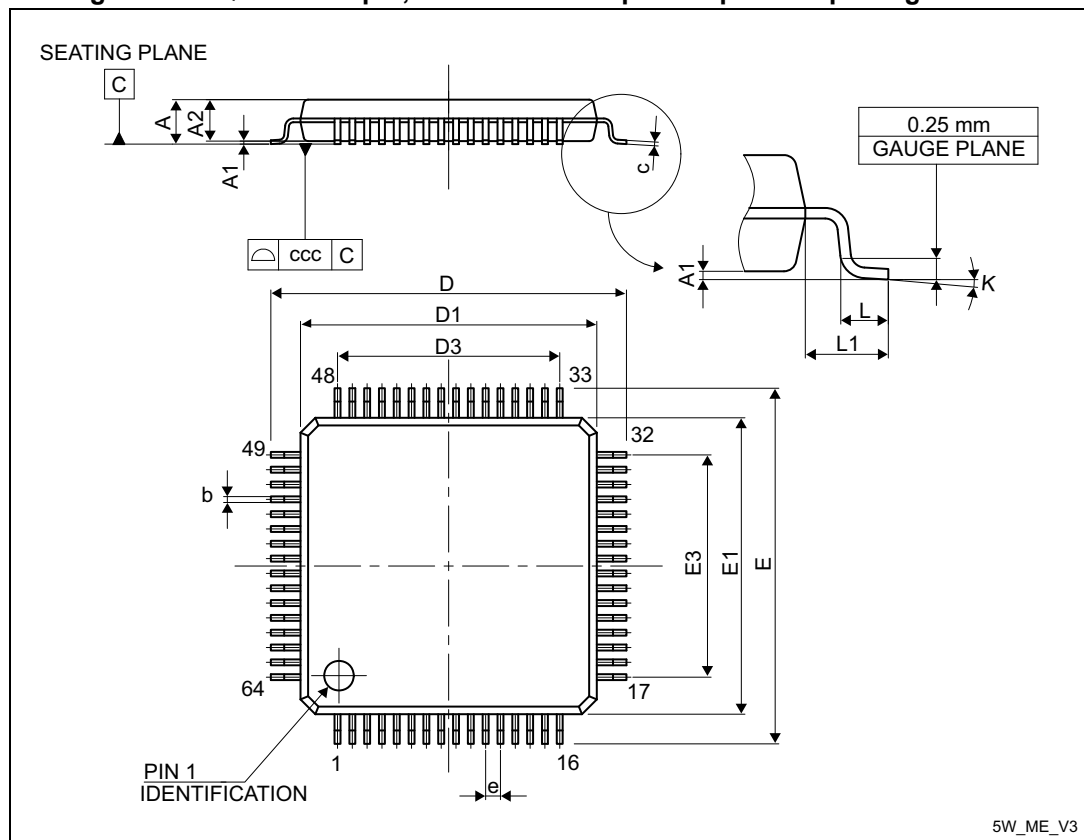
Refer to [Section 6.3.14: I/O port characteristics](#) for more details on the input/output characteristics.

Table 89. SD / MMC dynamic characteristics, $V_{DD}=2.7$ V to 3.6 V⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{PP}	Clock frequency in data transfer mode	-	0	-	50	MHz
-	SDIO_CK/fPCLK2 frequency ratio	-	-	-	4/3	-
$t_{W(CKL)}$	Clock low time	$f_{PP} = 50$ MHz	8	10	-	ns
$t_{W(CKH)}$	Clock high time	$f_{PP} = 50$ MHz	8	10	-	ns
CMD, D inputs (referenced to CK) in MMC and SD HS mode						
t_{ISU}	Input setup time HS	$f_{PP} = 50$ MHz	3.5	-	-	ns
t_{IH}	Input hold time HS	$f_{PP} = 50$ MHz	2.5	-	-	ns
CMD, D outputs (referenced to CK) in MMC and SD HS mode						
t_{OV}	Output valid time HS	$f_{PP} = 50$ MHz	-	12	13	ns
t_{OH}	Output hold time HS	$f_{PP} = 50$ MHz	10	-	-	ns
CMD, D inputs (referenced to CK) in SD default mode						
t_{ISUD}	Input setup time SD	$f_{PP} = 50$ MHz	3.5	-	-	ns
t_{IHD}	Input hold time SD	$f_{PP} = 50$ MHz	3	-	-	ns

7.3 LQFP64 package information

Figure 46. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package outline



1. Drawing is not to scale.

Table 94. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	-	12.000	-	-	0.4724	-
D1	-	10.000	-	-	0.3937	-
D3	-	7.500	-	-	0.2953	-
E	-	12.000	-	-	0.4724	-
E1	-	10.000	-	-	0.3937	-